



FORM PTO OFFICE PATENT & TRADEMARK OFFICE 1449	Atty. Docket No.: 169.12-0556	Application No.: 10/674,173 19/673,746
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor: Kalman Pelhos	
	Filing Date: September 29, 2003	Group Art: 2652 1753

U.S. PATENT DOCUMENTS

Examiner Initials	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents
AA			
AB			

FOREIGN PATENT DOCUMENTS

		Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Translation Yes No
SHV	AC	WO8007250	06-14-1994	Hitachi Ltd G115 566	No
SHV	AD	2002042326	07-19-00	KYOCERA CORP G115 578	Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

SHV	AE	Kiwamu Tanahashi, Yuzuru Hosoe, Masaaki Futamoto; <i>Magnetic Anisotropy and Microstructure of Obliquely Evaporated Co/Cr Thin Films</i> ; July 24, 1995; pgs. 265 - 272.
SHV	AF	Y.F. Zheng and J.P. Wang; <i>Control of the Tilted Orientation of CoCrPt/Ti thin film media by collimated sputtering</i> ; May 15, 2002; V931 pgs. 0007 - 0009.
SHV	AG	M.J. Hadley, R. Atkinson, R.J. Pollard; <i>Magnetic Properties of Co Films Deposited Onto Obliquely Sputtered Ta Underlayers</i> ; January 31, 2002.
SHV	AH	Dieter Weller and Andreas Moser; <i>Thermal Effect Limits in Ultrahigh-Density Magnetic Recording</i> ; November 1999; volume 35, pgs. 4423 - 4439.
SHV	AI	R.D. McMichael, C.G. Lee, J.E. Bonevich, P.J. Chen, W. Miller, and W.F. Egelhoff, Jr; <i>Strong Anisotropy in Thin Magnetic Films Deposited on Obliquely Sputtered Ta Underlayers</i> ; volume 88, No. 9, pgs. 5296 - 5299.0
SHV	AJ	A. Hagemeyer, H.J. Richter, H. Hibst, V. Maier and L. Marosi; <i>Crystallographic Texture and Morphology of Obliquely Deposited Co-Cr Magnetic Thin Films on Flexible Polymeric Substrates</i> ; August, 10, 1993; pgs. 199 - 202.
SHV	AK	T. Hikosaka, Y. Tamaka, T. Sonoda, and R. Nishikawa; <i>Cr Underlayer's Effect on the Magnetic and Crystalline Properties of Co Alloy Film</i> ; June 1988; volume 3, No. 6, pgs. 423 - 424.
SHV	AL	J.C. Lodder; <i>Magnetic Thin Films for High-Density Recording</i> ; 1996; pgs 474 -483

EXAMINER:

DATE CONSIDERED: June 20, 2005

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449	Atty. Docket No.: 169.12-0573	Application No.: 10/673,746
	First Named Inventor: Kalman Pelhos	
	Filing Date: Herewith <i>Sept. 29, 2002</i>	Group Art: 1753

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENT

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
<i>SHV</i>	AA	5,198,090	03/30/1993	Galicki et al.	204	298.11
<i>SHV</i>	AB	5,804,046	09/08/1998	Sawada et al.	204	298.11
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
<i>SHV</i>	AL	07-141610	02/06/1995	Japan	G11B 5/127	No
<i>SHV</i>	AM	09-212855	15/08/1997	Japan	G11B 5/182	No
<i>SHV</i>	AN	58-128023	30/07/1983	Japan	G11B 5/66	No
<i>SHV</i>	AO	2002-020864	23/01/2002	Japan	G23C 14/34	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>SHV</i>	AP	Y. F. Zheng and J. P. Wang and V. Ng; Control of the tilted orientation of CoCrPt/Ti thin film media by collimated sputtering; May 15, 2002; Journal of Applied Physics; Volume 91, Number 10
EXAMINER: <i>[Signature]</i>		DATE CONSIDERED: <i>June 29, 2005</i>

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FORM PTO-1449	Atty. Docket No.: 169.12-0573	Application No.: 10/673,746
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U.S. PATENT DOCUMENTS

Examiner Initials	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents
SHV	AA	US2003/0019745	Wang et al. 204/ 298.11
	AB		

FOREIGN PATENT DOCUMENTS

		Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Translation Yes No
SHV	AC	EP05280473	02-05-1995	Sony Corp. 623C 14/44	YES
SHV	AD	EP08298096	10-21-1996	Ricoh Co Ltd. 623C 14/34	YES
SHV	AE	EP06131571	12-01-1996	Hitachi LTD. 611B 5/66	YES

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

SHV	AF	PCT/US03/30489, Notification of Transmittal of the International Search Report or the Declaration, August 2004, pages 1-3.
SHV	AG	PCT/US03/30489, International Search Report, August 2004, pages 1-4.
SHV	AH	McMichael et al., Strong Anisotropy in Thin Magnetic Films Deposited on Obliquely Sputtered Ta Underlayers, November 2000, pages 5296-5299.

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